

Notice of References Cited	Application/Control No. 10/665,204	Applicant(s)/Patent Under Reexamination WANG ET AL.	
	Examiner A. Sefer	Art Unit 2826	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2003/0211648	11-2003	Buchanan et al.	438/48
	B	US-5,825,047	10-1998	Ajisawa et al.	257/12
	C	US-5,800,630	09-1998	Vilela et al.	136/249
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 6-90016	03-1994	Japan	Watanabe	
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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